2026 IEEE Workshop on Microelectronics and Electron Devices (WMED 2026)

Boise, Idaho, USA
10 April 2026

IEEE Catalog Number: CFP26564-POD
ISBN: 979-8-3195-2060-9

IEEE
Advancing Technology for Humanity

Copyright © 2026, IEEE

All Rights Reserved

Copyright and Reprint Permissions:

Abstracting is permitted with credit to the source. Libraries are permitted to photocopy beyond the limit of U.S. copyright law for private use of patrons those articles in this volume that carry a code at the bottom of the first page, provided the per-copy fee indicated in the code is paid through Copyright Clearance Center, 222 Rosewood Drive, Danvers, MA 01923.

For other copying, reprint or republication permission, write to IEEE Copyrights Manager, IEEE Service Center, 445 Hoes Lane, Piscataway, NJ 08854. All rights reserved.

*** This is a print representation of what appears in the IEEE Digital Library. Some format issues inherent in the e-media version may also appear in this print version.

IEEE Catalog Number:	CFP26564-POD
ISBN (Print-On-Demand):	979-8-3195-2060-9
ISBN (Online):	979-8-3195-2059-3
ISSN:	1947-3834

Additional Copies of This Publication Are Available From:

Curran Associates, Inc
57 Morehouse Lane
Red Hook, NY 12571 USA

Phone:	(845) 758-0400
Fax:	(845) 758-2633
E-mail:	curran@proceedings.com
Web:	www.proceedings.com



TABLE OF CONTENTS

On-chip data-path equalization using distributed and interleaved inverted feedback 1
Timothy M Hollis, Chulkyu Lee, Chris Holub

Study of Access Region Sheet Resistance in Superlattice U-GaN HEMT and its Compact Modeling 5
Vikram Magendar, Hiu Yung Wong

Design Tradeoffs of Through-Silicon-Carbide Vias for High-Temperature 3D SiC IC Integration 10
Sahithi Thota, Li Song, Feng Li

Machine Learning-Based Flaky Test Detection and Suppression for UVM Verification Regressions 14
Vikash Kumar, Yunus Akhtar, Ravi Gupta

Validation Proportion Matters: Generalization Stability of YOLO-Based Wafer Defect Detection with Limited Data 21
Chih-Kuan Ho, D. W. Parent